

Materials List for:

Measurement of X-ray Beam Coherence along Multiple Directions Using 2-D Checkerboard Phase Grating

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URL: <https://www.jove.com/video/53025>

DOI: [doi:10.3791/53025](https://doi.org/10.3791/53025)

Materials

Name	Company	Catalog Number	Comments
1-BM-B bending magnet X-ray source	Advanced photon Source/ Argonne National Lab		http://www.aps.anl.gov/Xray_Science_Division/Optics/Beamline/
LYSO Scintillator	Proteus Inc		http://www.apace-science.com/proteus/lyso.htm#top
Coolsnap HQ2 CCD detector	Photometrics		http://www.photometrics.com/products/ccdcams/coolsnap_hq2.php
ATC 2000 UHV sputtering deposition system	AJA International Inc		http://www.ajaint.com/systems_atc.htm
MICROPOSIT S1800 photoresist	Dow		
MICROPOSIT 351 developer	Dow		
MA/BA6 lithography system	SUSS MicroTec		http://www.suss.com/en/products-solutions/products/mask-aligner/maba6/overview.html
Spin coater WS-400-6NPPB	Laurell Technologies Corporation		http://www.laurell.com/spin-coater/?model=WS-400-6NPP-LITE
JBX-9300FS electron beam lithography system	JEOL		http://www.jeolusa.com/PRODUCTS/PhotomaskDirectWriteLithography/ElectronBeamLithography/JBX-9500FS/tabid/245/Default.aspx
CS-1701 RIE system	Nordson March		http://www.nordson.com/EN-US/DIVISIONS/MARCH/PRODUCTS/LEGACY/Pages/CS-1701-Anisotropic-RIE-Plasma-System.aspx
Techni Gold 25E	Technic		http://www.technic.com/eu/applications/industrial/industrial-chemistry/plating-chemistry
Dektak-8 surface profiler	Bruker		http://brukersupport.com/ProductDetail/1136
MICROPOSIT 1165 remover	Dow		